

# Imaging Ellipsometry for full wafer analysis of Graphene and hexagonal Boron-Nitride

Sebastian Funke<sup>1</sup>, Philipp Braeuninger-Weimer<sup>2</sup>, Peter H. Thiesen<sup>1</sup>, Stephan Hofmann<sup>2</sup>

<sup>1</sup>Accurion GmbH, Stresemannstraße 30, Göttingen, Germany

<sup>2</sup>Department of Engineering, University of Cambridge, Cambridge CB3 0FA, United Kingdom  
[sfu@accurion.com](mailto:sfu@accurion.com)

Imaging ellipsometry (IE) combines the resolution of an optical microscope with the sensitivity of ellipsometry for thin films. It allows to measure monolayers of 2D-materials but also to visualize these monolayers on arbitrary substrates. It overcomes the need of specially tuned SiO<sub>2</sub> thicknesses to visualize e.g. Graphene in an optical microscope.

In the talk we present [1], that IE is able to characterize Graphene throughout all stages of the manufacturing process from the growth on Cu-foil up to the transferred sample on Si wafers. Unlike other methods we can directly visualize graphene on the rough Cu. Figure 1 shows a large area map of Graphene on Cu. The Graphene is directly characterized on the Cu-foil, no oxidation of the Cu is needed. To overcome the waviness of the foil, an autofocus algorithm is developed and applied.

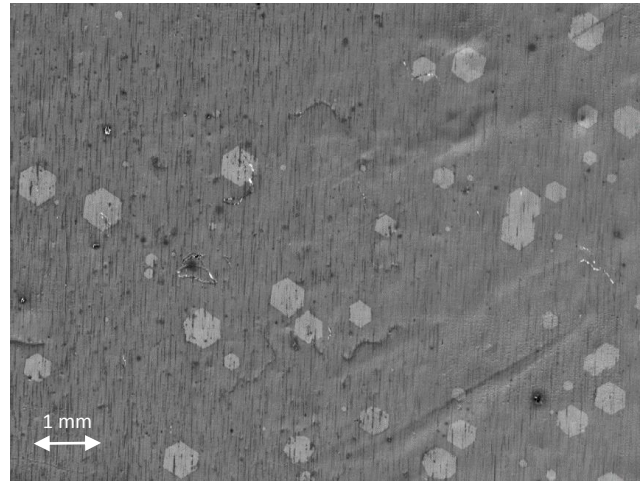
Figure 2 shows a Graphene monolayer and hBN monolayer after the transfer process to a Si/SiO<sub>2</sub> substrate. The contrast mode of IE is able to distinguish the different regions: (a) substrate only, (b) hBN only, (c) Graphene only and (d) an overlapping region of hBN and Graphene. The complete sample approx. 1cm x 0.8 cm is recorded in less than 6 minutes and shows defects and wrapping of hBN of a size as small as 4 μm.

Lastly, we demonstrate that this method can be used to characterise full 4" wafers of graphene on Si within short time spans at 4 μm resolution.

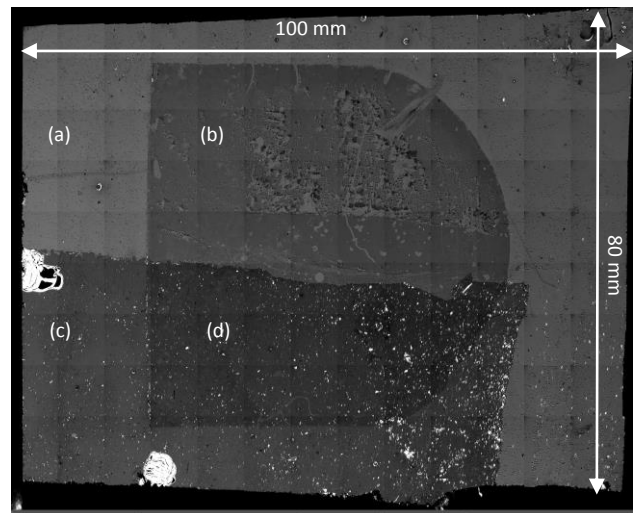
References

[1] Braeuninger, Funke, et al. *submitted*.

Figures



**Figure 1:** IE measurement of graphene on Cu prior to oxidation



**Figure 2:** hBN and Graphene monolayer on Si/SiO<sub>2</sub> substrate. Visualized in less than 6 minutes. (a) substrate only, (b) hBN only, (c) Graphene only and (d) monolayer graphene on monolayer hBN.